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(71)Applicant : HITACHI LTD

HITACHI VIDEO & INF SYST INC

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(72)Inventor : WATABE YOSHIHISA

ITO YASUYUKI

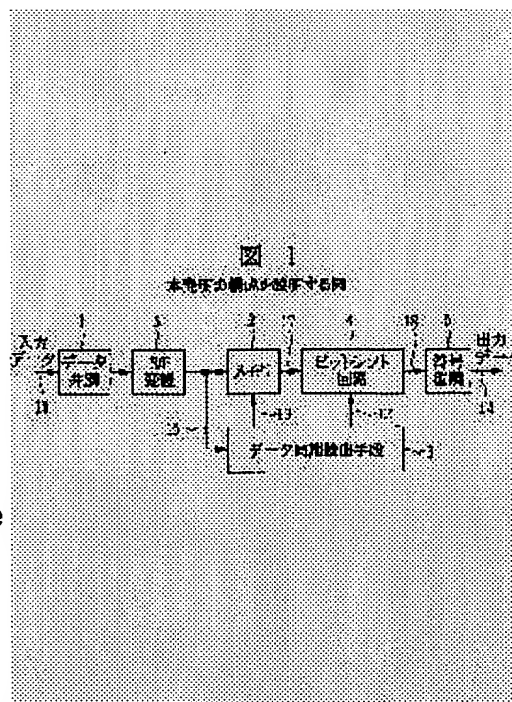
(54) DATA SYNCHRONISM DETECTING METHOD, DATA SYNCHRONISM DETECTING DEVICE, INFORMATION RECORDING METHOD AND DEVICE, INFORMATION REPRODUCING METHOD AND DEVICE, INFORMATION RECORDING FORMAT, SIGNAL PROCESSING DEVICE, INFORMATION RECORDING REPRODUCING DEVICE, AND INFORMATION STORAGE MEDIUM

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a data synchronism detecting technique having little data synchronism detection error and improved format efficiency.

SOLUTION: A data synchronism detecting means 3 detecting data synchronism by using code-modulated data themselves is provided between a data discriminating means 1 and a code-demodulating means 6 of a data regeneration system. Specific bit patterns occurring in data code words are counted for each phase (bit) by using specific bit train patterns not occurring in a specific phase of the data code words by the conversion rule at code modulation (or specific bit train patterns occurring only in the specific phase of the code words) to

specify the pause positions of the data code words. Write data are scrambled as required to ensure synchronism detection. The pattern correlation between a PLO(phase-locked oscillator)-SYNC section and a GAP section is detected to specify a data position. A sector format formed with PLO-SYNC, DATA, ECC, and GAP having no data synchronization signal can be used.



LEGAL STATUS

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